

2nd International Workshop on DEPFET Detectors and Applications

Monday, 4 May 2009

DEPFET cont. / ASIC Design and Testresults - Lecture Room (14:00 - 15:30)

time	[id] title	presenter
14:00	[22] DEPFET Parameter Extraction	WASSATSCH, Andreas
14:15	[4] DCD and Switcher Status	PERIC, Ivan
14:45	[14] DHP Development	KRUEGER, Hans
15:05	[9] DCD2 Testsystem and Results	KOCH, Manuel